Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	er	
10/649,198	KOUGIOURIS ET AL.	ET AL.	
Examiner	Art Unit		
Maikhanh Nauven	2176		

SEARCHED				
Class	Subclass	Date	Examiner	
715	513	8/20/2005	мк	
·	526,531	8/20/2005	MK	
715	700,760	8/20/2005	MK	
	861	8/20/2005	MK	
709	203	8/20/2005	MK	
Updated	above	4/27/2006	MK	
Updated	above	2/10/2007	MK	
Updated	above	2/14/2008	MK	
			:	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
Inventor Name Search	8/20/2005	мк		
West Search (See search history printout)	8/20/2005	МК		
NPL (IEEE)	8/20/2005	MK		
NPL (IEEE)	4/27/2006	MK		
West Updated (USPAT, PG-PUB, EPO, JPO, DERWENT, IBM_TDB	4/27/2006	MK		
West Updated (USPAT, PG-PUB, EPO, JPO, DERWENT, IBM_TDB	2/10/2007	MK		
West Updated (USPAT, USPGPub) See Search History Printout	2/14/2008	мк		